## Notice of References Cited Application/Control No. Applicant(s)/Patent Under Reexamination TAKANO ET AL. Examiner AHMED ELALLAM Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,141,555 A	10-2000	Sato, Toshifumi	455/437
*	В	US-6,154,653 A	11-2000	Jung, Jin Soo	455/442
*	С	US-6,198,928 B1	03-2001	Keurulainen et al.	455/436
*	D	US-6,216,004 B1	04-2001	Tiedemann et al.	455/442
*	E	US-6,456,606 B1	09-2002	Terasawa, Daisuke	370/331
*	F	US-6,546,058 B1	04-2003	Gilhousen et al.	375/285
*	G	US-6,577,868 B1	06-2003	Vialen et al.	455/441
*	r	US-6,574,211 B2	06-2003	Padovani et al.	370/347
*	_	US-6,714,788 B2	03-2004	Voyer, Nicolas	455/453
*	J	US-6,728,227 B1	04-2004	Ohtani et al.	370/331
*	К	US-6,895,246 B2	05-2005	Bonta, Jeffrey D.	455/442
	با	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Ρ					
	Q					
	R					
	S					
	Т	***				

## **NON-PATENT DOCUMENTS**

_	HON-I ATENT BOOMENTO							
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	V							
	w							
	x							

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.